

Applicant: Mid Ocean Brands B.V.

Product: USB HUB

Trademark: N/A

Model No.: MO8853

Test Standards: EN 55032:2015+A11:2020+A1:2020

EN IEC 61000-3-2:2019 +A1:2021

EN 55035:2017+A11:2020

EN 61000-3-3:2013+A2:2021+AC:2022-01

Test Result:

The EMC testing has been performed on the submitted

samples and found in compliance with council EMC Directive

2014/30/EU.

Approved By

Terry Tang

Manager

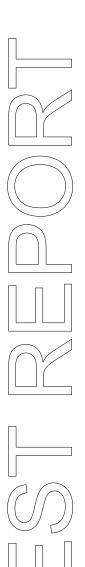
Dated: December 27, 2024

Results appearing herein relate only to the sample tested The technical reports is issued errors and omissions exempt and is subject to withdrawal at

SHENZHEN TIMEWAY TESTING LABORATORIES

Zone C, 1st Floor, Block B, Jun Xiang Da Building, Zhongshan Park Road West, Tong Le Village, Nanshan District, Shenzhen, China

Tel (755) 83448688, Fax (755) 83442996, E-Mail:info@timeway-lab.com



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Date: 2024-12-27



Special Statement:

FCC-Registration No.: 744189

The EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications commission. The acceptance letter from the FCC is maintained in our files. Registration No.: 744189.

Industry Canada (IC) — Registration No.:5205A

The EMC Laboratory has been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 5205A.

A2LA (Certification Number:5013.01)

The EMC Laboratory has been accredited by the American Association for Laboratory Accreditation (A2LA). Certification Number:5013.01

CAB identifier: CN0033

Date: 2024-12-27



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1.0 General Details

1.1 Test Lab Details

SHENZHEN TIMEWAY TESTING LABORATORIES

Zone C, 1st Floor, Block B, Jun Xiang Da Building, Zhongshan Park Road West, Tong Le Village, Nanshan

District, Shenzhen, China

Tel: +86 755 83448688 Fax: +86 755 83442996

Test Location

All tests were performed at:

SHENZHEN TIMEWAY TESTING LABORATORIES

Zone C, 1st Floor, Block B, Jun Xiang Da Building, Zhongshan Park Road West, Tong Le Village, Nanshan

District, Shenzhen, China

Tel: +86 755 83448688 Fax: +86 755 83442996

1.2 Applicant Details

Applicant: Mid Ocean Brands B.V.

Address: 7/F., Kings Tower, 111 King Lam Street, Cheung Sha Wan, Kowloon, Hong Kong

Manufacturer: Mid Ocean Brands B.V.

Address: 7/F., Kings Tower, 111 King Lam Street, Cheung Sha Wan, Kowloon, Hong Kong

1.3 Description of EUT

Product: USB HUB

Trademark: N/A

Model Number: MO8853

Adding Trademark: N/A
Adding Model Number: N/A

Rating: Input: DC5V

1.4 Submitted Sample(s)

1 Sample

1.5 Test Duration

Date of Receipt of Application: December 23, 2024 Date of Test: December 23, 2024 ~ December 27, 2024

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1.6 Additional information of EUT

1.7

	Submitted	Not Available
User Manual	\boxtimes	
Part List		
Circuit Diagram	\boxtimes	
Printed circuit board	\boxtimes	
[PCB] Layout		
Block Diagram		
Test Engineer	^	0
The sample(s) tested by	feo	. Lon

This test report is not valid without personnel's signatures of SHENZHEN TIMEWAY TESTING LABORATORIES.

Print Name: Leo Lau/ Engineer

Date: 2024-12-27



2.0 List of Measurement Equipment

2.1 Conducted Emission Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESCS 30	834115/006	RS	2024.07.12	1Year
LISN	NNB42	00012	SCHAFFNER	2024.07.12	1Year

2.2 Radiated Disturbance Test

				Calibration	Calibration
Name	Model No	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESPI 3	100379	RS	2024.07.12	1Year
Spectrum Analyzer	E4407B	MY50441392	HP/Agilent	2024.07.12	1Year
Amplifier	BBV9743	#218	HP/Agilent	2024.07.12	1Year
Bilog Antenna	VULB9163	9163/340	Schwarebeck	2022.07.18	3Year
Horn Antenna	BBHA 9120D	9120D-631	RS	2022.07.18	3Year
Amplifier	8449B	3008A00160	HP/Agilent	2024.07.12	1Year

2.3 Harmonic & Flicker Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Harmonics Flicker Test					
System	PACS-1	72305	CI	2024.07.12	1Year
5K VA AC Power					
Source	5001iX	56060	CI	2024.07.12	N/A

2.4 ESD Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
ESD Simulator	ESS-2002	ESS06Y6394	NoiseKen	2024.07.12	1Year

2.5 RF field Strength Susceptibility

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Signal Generator	SMT03	100059	RS	2024.07.12	1Year
Power Meter	NRVS		RS	2024.07.12	1Year
Voltage Probe	URV5-Z2	100012	RS	2024.07.12	1Year

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Voltage Probe	URV5-Z2	100013	RS	2024.07.12	1Year
Power Amplifier	150W1000	300999	AR	2024.07.12	1Year
Power Amplifier	25S1G4AM1	305993	AR	2024.07.12	1Year
Field Probe	CBL6111C	2576	Holaday	2024.07.12	1Year
Bilog Antenna	MCDC		Chase	2024.07.12	1Year

2.6 Electrical Fast Transient/Burst (EFT/B) Immunity test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EFT Generator	UCS 500 M4	0304-42	EM TEST	2024.07.12	1Year
Power Source	MV2616	0104-14	EM TEST	2024.07.12	1Year

2.7 Surge Test

					Calibration
Name	Model No.	Serial No.	Manufacturer	Calibration Date	Cycle
Ultra Compact	UCS 500				
Simulator	M4	0304-42	EM TEST	2024.07.12	1Year
Power Source	MV2616	0104-14	EM TEST	2024.07.12	1Year

2.8 Conducted Immunity Test

					Calibration	Calibration
Name		Model No.	Serial No.	Manufacturer	Date	Cycle
Continuous	Wave					
Simulator		CWS 500C	0407-05	EM TEST	2024.07.12	1 Year

2.9 Power-frequency Magnetic Field

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Continuous Wave					
Simulator	UCS 500 M4	0304-42	EM TEST	2024.07.12	1 Year
Power Source					
Network	MV 2616	0104-14	EM TEST	2024.07.12	1 Year
Current Transformer	MC2630		EM TEST	2024.07.12	1 Year
Magnetic Coil	MS100	0304-42	EM TEST	2024.07.12	1 Year

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2.10 Voltage Dips/Interruption Immunity Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Ultra Compact					
Simulator	UCS 500 M4	0304-42	EM TEST	2024.07.12	1Year
Power Source	MV2616	0104-14	EM TEST	2024.07.12	1Year

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3.0 **Technical Details**

3.1 Investigations Requested

Perform Electromagnetic Interference [EMI] & Electromagnetic Susceptibility [EMS] tests for CE Marking

3.2 Test Standards

	Test Standards		
EN 55032:2015+A11:2020+A1:2020		ty of multimedia equipment - Emission	
	Requirements		
	Electromagnetic compatibil	lity(EMC)- Part 3-2:Limits-Limits for	
EN IEC 61000-3-2:2019+ A1:2021	harmonic current emission	s(equipment input current ≤ 16A per	
	phase)		
	Electromagnetic compatibili	ty (EMC)- Part 3-3: Limits-Limitation of	
EN 61000-3-3:2013	voltage changes, Voltage	fluctuations and flicker in public	
+A2:2021+AC:2022-01	low-voltage supply systems. For equipment with rated current ≤		
	16A per phase and not subject to conditional connection		
EN 55025-2017 A 11-2020	Electromagnetic compatibili	ty of multimedia equipment - Immunity	
EN 55035:2017+A11:2020	requirements		
	EN 61000-4-2:2009	Electrostatic discharge	
	EN IEC 61000-4-3:2020	RF electromagnetic field disturbances	
	EN 61000-4-4:2012	Electrical Fast transients	
	EN 61000-4-5:2014	Surge	
	EN 61000-4-6:2014 Conducted susceptibility		
	EN 61000-4-8:2010	Power-frequency Magnetic Field	
	EN IEC 61000-4-11: 2020	Dips/Voltage Interruption Variation	

3.3 **Performance Criteria**

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

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3.4 **Test standards and Results Summary Tables**

Date: 2024-12-27

Test Condition	Test Requirement	Test Method	Test Result			
EMISSION Results Summary						
Conducted Emission on AC	EN 55032:2015	EN 55032:2015	Pass			
Mains, 150kHz to 30MHz	+A11:2020+A1:2020	+A11:2020+A1:2020	Pass			
Conducted Emission on at	EN 55032:2015	EN 55032:2015				
telecommunication ports,	+A11:2020+A1:2020	+A11:2020+A1:2020	N/A			
150kHz to 30MHz						
Radiated Emissions,	EN 55032:2015	EN 55032:2015	Pass			
30MHz to 6GHz	+A11:2020+A1:2020	+A11:2020+A1:2020	Pass			
Harmonic Emissions on AC	EN IEC 61000-3-2:2019	EN IEC 61000-3-2:2019	N/A			
supply	+A1:2021	+A1:2021	N/A			
Voltage fluctuations on AC	EN 61000-3-3:2013	EN 61000-3-3:2013	NT/A			
supply	+A2:2021+AC:2022-01	+A2:2021+AC:2022-01	N/A			
	IMMUNITY Results Sum	mary				
Electrostatic Discharge	EN 55035:2017+A11:2020	EN 61000-4-2: 2009	Pass			
Continuous RF electromagnetic	EN 55035:2017+A11:2020	EN IEC 61000-4-3:2020	Pass			
field disturbances			Pass			
Continuous induced RF	EN 55035:2017+A11:2020	EN 61000-4-6:2014	Pass			
disturbances						
Power frequency magnetic field	EN 55035:2017+A11:2020	EN 61000-4-8: 2010	N/A			
Electrical fast transients/burst	EN 55035:2017+A11:2020	EN 61000-4-4: 2012	Pass			
(EFT/B)						
Surges	EN 55035:2017+A11:2020	EN 61000-4-5: 2014	Pass			
Voltage dips and interruptions	EN 55035:2017+A11:2020	EN IEC 61000-4-11: 2020	Pass			
Broadband impulsive conducted disturbances	EN 55035:2017+A11:2020	EN 61000-4-6:2014	N/A			

Note: N/A-Not applicable

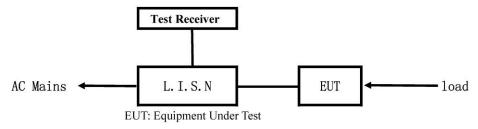
Date: 2024-12-27



4.0 Electromagnetic Interference Test results

4.1 Power line Conducted Emission Test

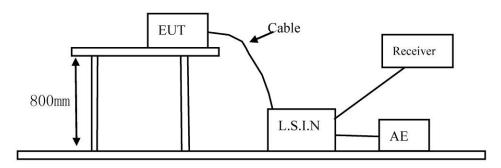
4.1.1 Schematics of the test



4.1.2 Test Method:

The test was performed in accordance with EN 55032:2015+A11:2020+A1:2020

Block diagram of Test setup



4.1.3 Power line conducted Emission Limit

	Limits dB(μ V)					
Frequency(MHz)	Class A l	Class A Equipment		quipment		
	Quasi-peak Level	Average Level	Quasi-peak Level	Average Level		
$0.15 \sim 0.50$	79.0	66.0	66.0~56.0*	56.0~46.0*		
$0.50 \sim 5.00$	73.0	60.0	56.0	46.0		
5.00 ~ 30.00	73.0	60.0	60.0	50.0		

Notes: 1. *decreasing linearly with logarithm of frequency.

2. The lower limit shall apply at the transition frequencies

4.1.4 Test Results

Limits for Conducted Emission test, please refer to limit line (Quasi-peak) and Average in the following diagram labelled as (QP)&AV

Remark: Calculated measurement uncertainty=3.6dB

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A: Disturbance Voltage Limits at mains on Live terminals (150kHz to 30MHz)

EUT Operating Environment

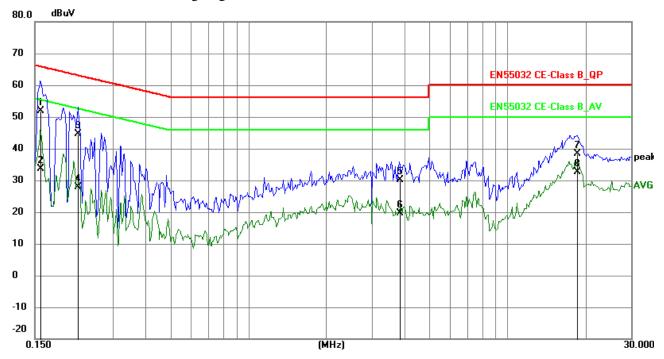
Temperature: 25°C Humidity: 65%RH Atmospheric Pressure: 101 kPa

EUT set Condition: Data Transmission with PC (Max Load)

Power: AC230V/50Hz Equipment Level: Class B

Results: Pass

Please refer to following diagram for individual



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB)	Level (dBuV)	Limit (dBuV)	Margin (dB)	Detector	P/F
1	0.1578	41.49	10.34	51.83	65.58	-13.75	QP	Р
2	0.1578	23.26	10.34	33.60	55.58	-21.98	AVG	Р
3	0.2202	34.19	10.33	44.52	62.81	-18.29	QP	Р
4	0.2202	17.64	10.33	27.97	52.81	-24.84	AVG	Р
5	3.8229	18.14	11.97	30.11	56.00	-25.89	QP	Р
6	3.8229	7.54	11.97	19.51	46.00	-26.49	AVG	Р
7	18.5961	22.43	16.07	38.50	60.00	-21.50	QP	Р
8	18.5961	16.52	16.07	32.59	50.00	-17.41	AVG	Р

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B: Disturbance Voltage Limits at mains on Neutral terminals (150kHz to 30MHz)

EUT Operating Environment

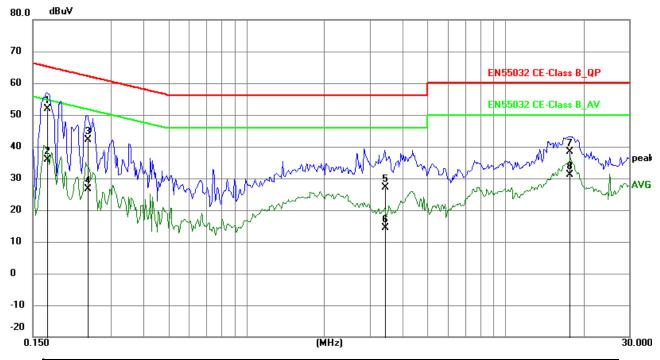
Temperature: 25°C Humidity: 65%RH Atmospheric Pressure: 101 kPa

EUT set Condition: Data Transmission with PC (Max Load)

Power: AC230V/50Hz Equipment Level: Class B

Results: Pass

Please refer to following diagram for individual



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB)	Level (dBuV)	Limit (dBuV)	Margin (dB)	Detector	P/F
1	0.1695	41.64	10.33	51.97	64.98	-13.01	QP	Р
2	0.1695	25.65	10.33	35.98	54.98	-19.00	AVG	Р
3	0.2436	31.79	10.33	42.12	61.97	-19.85	QP	Р
4	0.2436	16.24	10.33	26.57	51.97	-25.40	AVG	Р
5	3.4212	15.40	11.82	27.22	56.00	-28.78	QP	Р
6	3.4212	2.46	11.82	14.28	46.00	-31.72	AVG	Р
7	17.5704	22.48	15.80	38.28	60.00	-21.72	QP	Р
8	17.5704	15.39	15.80	31.19	50.00	-18.81	AVG	Р

The report refers only to the sample tested and does not apply to the bulk.

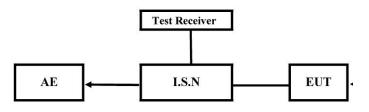
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4.2 **Telecommunication ports Conducted Emission Test**

4.2.1 **Schematics of the test**

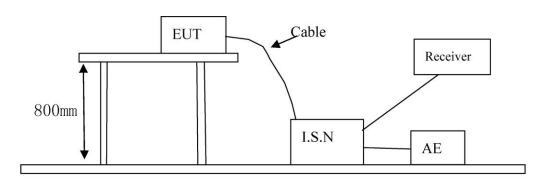


EUT: Equipment Under Test

4.2.2 Test Method:

The test was performed in accordance with EN 55032:2015+A11:2020+A1:2020

Block diagram of Test setup



Telecommunication ports conducted Emission Limit

	Class A Limits				Class B Limits			
Frequency	Quasi-pe	Quasi-peak Level Average Level		e Level	Quasi-peak Level		Average Level	
(MHz)	Voltage dB(uV)	Current dB(uA)	Voltage dB(uV)	Current dB(uA)	Voltage dB(uV)	Current dB(uA)	Voltage dB(uV)	Current dB(uA)
0.15 ~ 0.50	97 to 87	53 to 43	87 to 74	40 to 30	84 to 74	40 to 30	74 to 64	30 to 20
0.50 ~ 30.00	87	43	74	30	74	30	64	20

- Notes: 1.*decreasing linearly with logarithm of frequency.
 - 2. The tighter limit shall apply at the transition frequencies

4.2.4 Test Results: N/A

Limits for Conducted Emission test, please refer to limit line (Quasi-peak) and Average in the following diagram labelled as (QP)&AV

Remark:

Calculated measurement uncertainty=1.9dB

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Conducted Emission on Telecommunication port (150kHz to 30MHz)

EUT Operating Environment

Temperature: 25°C Humidity: 75 %RH Atmospheric Pressure: 101 kPa

EUT set Condition: Normal operation mode

Equipment Level: Class B

Results: N/A

Please refer to following diagram for individual

Frequency	Port	Reading(dBµV)		Limit(dBµV)	
(MHz)	ron	Quasi-peak	Average	Quasi-peak	Average

Date: 2024-12-27



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B: Conducted Emission on Telecommunication port (150kHz to 30MHz)

EUT Operating Environment

Temperature: 25°C Humidity: 75 %RH Atmospheric Pressure: 101 kPa

EUT set Condition: Normal operation mode

Equipment Level: Class B

Results: N/A

Please refer to following diagram for individual

Frequency	Port	Reading(dBµA)		Limit(dBµA)	
(MHz)	FOIT	Quasi-peak	Average	Quasi-peak	Average

Note: This test item is not applicable because there is no telecommunication port

Date: 2024-12-27



4.3 Radiated Disturbance Test

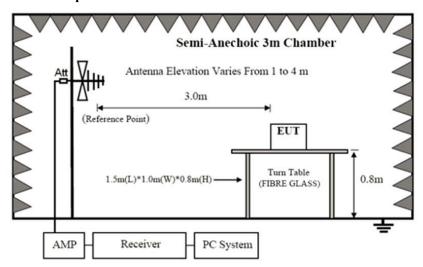
4.3.1 Schematics of the test



4.3.2 Test Method:

The test was performed in accordance with EN 55032:2015+A11:2020+A1:2020

Block diagram of Test setup



4.3.3 Radiated Disturbance Test Limit

Frequency Range (MHz)	Quasi-Peak limits (dB μ V/m)		
	Class A Limits	Class B Limits	
30-230	50.00	40.00	
230-1000	57.00	47.00	
1000-3000	56(AV)/76(PK)	50(AV)/70(PK)	
3000-6000	60(AV)/80(PK)	54(AV)/74(PK)	

Note: The lower limit shall apply at the transition frequencies

4.3.4 Test result

Limits for Radiated Disturbance test, please refer to limit line (Quasi-peak) in the following diagram labelled as (QP)

Remark:

Calculated measurement uncertainty=4.7dB

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Date: 2024-12-27



A: Radiated Disturbance (30MHz----1000MHz)

Project Number: CASE3 Test Time: 2024-12-24_16.29.56

EUT Name: USB HUB Test Engineer: BETTY

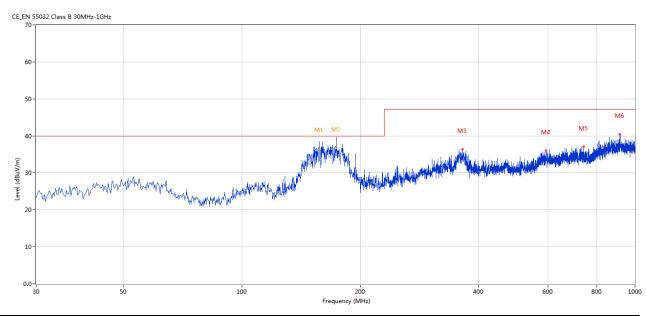
Manufacturer: Mid Ocean Brands B.V. Test Standard: EN 55032

Model: MO8853 Work Addition: Data Transmission with

PC (Max Load)

Temp.($^{\circ}$ C): 25 Load:

Hum.: 65% Test Voltage: 230V/50Hz



No.	Frequency	Results	Factor	Limit	Margin	Detector	Table	Height	Antenna	Verdict
	(MHz)	(dBuV/m)	(dB)	(dBuV/m)	(dB)		(Degree)	(cm)		
1*	157.523	36.61	-9.63	40.0	3.39	QP	1.00	100	Horizontal	Pass
2*	174.009	36.72	-8.50	40.0	3.28	QP	11.00	100	Horizontal	Pass
3	364.324	36.33	-1.82	47.0	10.67	Peak	1.00	100	Horizontal	Pass
4	594.399	36.02	1.53	47.0	10.98	Peak	1.00	100	Horizontal	Pass
5	740.347	37.10	2.57	47.0	9.90	Peak	46.00	100	Horizontal	Pass
6	913.934	40.48	5.35	47.0	6.52	Peak	26.00	100	Horizontal	Pass

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Date: 2024-12-27



B: Radiated Disturbance (30MHz----1000MHz)

Project Number: CASE3 Test Time: 2024-12-24_16.27.57

EUT Name: USB HUB Test Engineer: BETTY

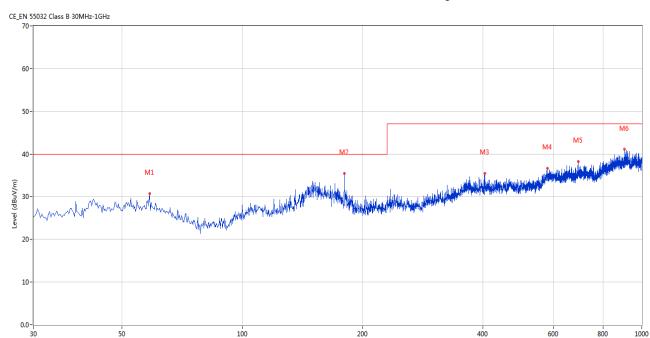
Manufacturer: Mid Ocean Brands B.V. Test Standard: EN 55032

Model: MO8853 Work Addition: Data Transmission with

PC (Max Load)

Temp.($^{\circ}$ C): 25 Load:

H m.: 65% Test Voltage: 230V/50Hz



No.	Frequency	Results	Factor	Limit	Margin	Detector	Table	Height	Antenna	Verdict
	(MHz)	(dBuV/m)	(dB)	(dBuV/m)	(dB)		(Degree)	(cm)		
1	58.608	30.70	-5.11	40.0	9.30	Peak	321.00	100	Vertical	Pass
2	180.070	35.45	-8.06	40.0	4.55	Peak	308.00	100	Vertical	Pass
3	405.296	35.44	-1.51	47.0	11.56	Peak	340.00	100	Vertical	Pass
4	580.580	36.61	1.65	47.0	10.39	Peak	276.00	100	Vertical	Pass
5	693.072	38.20	2.13	47.0	8.80	Peak	82.00	100	Vertical	Pass
6	904.479	41.07	4.91	47.0	5.93	Peak	180.00	100	Vertical	Pass

Frequency (MHz)

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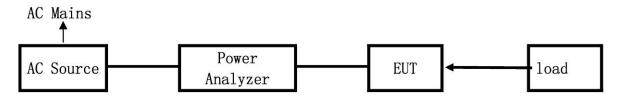
Report No.: TWN2412680E

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4.4 **Harmonic Current Emission Test**

4.4.1 **Schematic of the test**

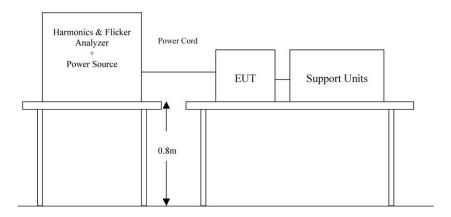


EUT: Equipment Under Test

4.4.2 Test Method:

The test was performed in accordance with EN IEC 61000-3-2:2019 +A1:2021

Block diagram of Test setup



Limits of Harmonic Current Emission For Class A

Date: 2024-12-27



Harmonic order	Maximum permissible harmonic current		
n	Α		
Odd har	monics		
3	2,30		
5	1,14		
7	0,77		
9	0,40		
11	0,33		
13	0,21		
15 ≤ n ≤ 39	0,15 <u>15</u>		
Even har	monics		
2	1,08		
4	0,43		
6	0,30		
8 ≤ n ≤ 40	0,23 8 n		

4.4.4 **Test Results**

Please refer to the following pages

Harmonic Current Emission Test

EUT Operating Environment

Temperature: 25°C Humidity: 53%RH Atmospheric Pressure: 101 kPa

EUT set Condition:

Results: N/A

N/A --- the input power less than 75W.

Please refer to following diagram for individual

Harmonic results as a% of the limits

No	(Test	No	(Test	No	(Test	No	(Test
	result/Limit) %		result/Limit) %		result/Limit) %		result/Limit) %
1		11		21		31	
2		12		22		32	
3		13		23		33	
4		14		24		34	
5		15		25		35	
6		16		26		36	
7		17		27		37	
8		18		28		38	
9		19		29		39	
10		20		30		40	

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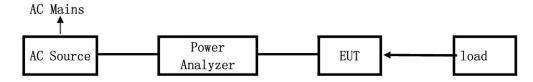
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4.5 Voltage Fluctuations & Flicker Test

4.5.1 Schematic of the test

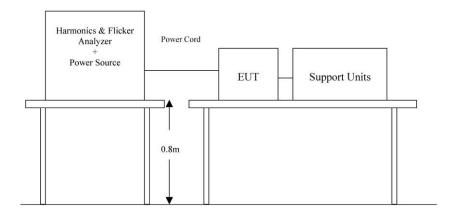


EUT: Equipment Under Test

4.5.2 Test Method:

The test was performed in accordance with EN 61000-3-3:2013+A2:2021+AC:2022-01

Block diagram of Test setup



4.5.3 Test Results

Result: N/A

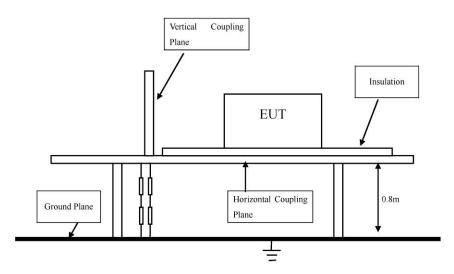
Date: 2024-12-27



5.0 Immunity Test

5.1 Electrostatic Discharge

5.1.1 Schematic of the test



5.1.2 Test method

The test was performed in accordance with EN 61000-4-2: 2009

5.1.3 Test severity

±4kV for direct & in-direct Contact Discharge

 $\pm 8 \text{kV}$ for air Discharge

Performance Criterion Require: **B** (Please see following table)

5.1.4 Susceptibility performance Criteria and Severity level

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

Level	Test Voltage Direct & in-direct contact	Test Voltage Air
	Discharge (kV)	discharge(kV)
1	$\pm 2 \mathrm{kV}$	$\pm 2kV$
2	±4kV	$\pm 4 \mathrm{kV}$
3	$\pm 6 \mathrm{kV}$	$\pm 8 \mathrm{kV}$
4	$\pm 8 \mathrm{kV}$	$\pm 15 \mathrm{kV}$

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5.1.5 Test Result

EUT Operating Environment

Temperature: 25 °C Humidity: 53%RH Atmospheric Pressure: 101 kPa

Please refer to the following table for individual results.

Location	Discharge Method	Test Voltage	Results
HCP (Horizontal coupling plane)	In-Direct	$\pm 2kV, \pm 4kV$	Pass
VCP (Vertical Coupling Plane)	In-Direct	$\pm 2kV, \pm 4kV$	Pass
Type-C Port	Contact Discharge	$\pm 2kV, \pm 4kV$	Pass
Enclosure	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass
Gaps	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass

Remark: Calculated measurement uncertainty= 0.2kV

Date: 2024-12-27



5.2 RF field strength susceptibility (80MHz-1000MHz, 1800MHz, 2600MHz, 3500MHz, 5000MHz)

5.2.1 Schematics of the test



EUT: Equipment Under Test

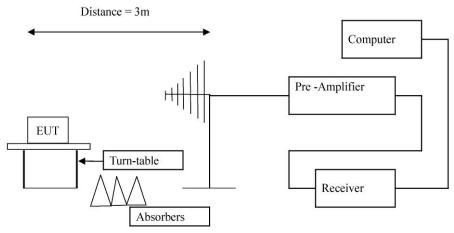
5.2.2 Test Method:

The test was performed in accordance with EN IEC 61000-4-3:2020

Severity: Level 2 (3V/m) Modulation: 80% AM

Performance Criterion Require: A (Please see following table)

Block diagram of Test setup



5.2.3 Susceptibility performance Criteria and severity Level

Susceptibility performance Criteria

Criterion	Description				
A	A No change in operational mode or degradation of performance outside of specification and no change in stored parameters.				
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.				
C Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.					

Severity Level

Level	Field Strength (V/m)
1	1
2	3
3	10

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5.2.4 Test Result:

EUT Operating Environment

Temperature: 25 °C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following table for individual results.

Frequency	Face	Polarity	Level	Dwell	Sweep	Results
(MHz)			(V/m)	Time(s)	Rate (%)	
80-1000	0°	Horizontal	3	1	1	Pas
80-1000	90°	Horizontal	3	1	1	Pass
80-1000	180°	Horizontal	3	1	1	Pass
80-1000	270°	Horizontal	3	1	1	Pass
80-1000	0°	Vertical	3	1	1	Pass
80-1000	90°	Vertical	3	1	1	Pass
80-1000	180°	Vertical	3	1	1	Pass
80-1000	270°	Vertical	3	1	1	Pass
1800,	0°	Horizontal	3	1	1	Pass
2600,	90°	Horizontal	3	1	1	Pass
3500,	180°	Horizontal	3	1	1	Pass
5000	270°	Horizontal	3	1	1	Pass
1800,	0°	Vertical	3	1	1	Pass
2600,	90°	Vertical	3	1	1	Pass
3500,	180°	Vertical	3	1	1	Pass
5000	270°	Vertical	3	1	1	Pass

Date: 2024-12-27



5.3 Electrical Fast Transient/Burst (EFT/B) immunity test

5.3.1 Schematics of the test



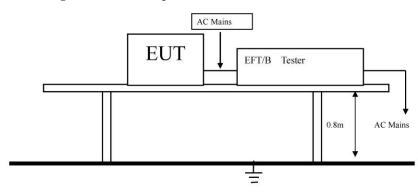
5.3.2 Test Method

The test was performed in accordance with EN 61000-4-4:2012

Severity: Level 2 (1kV)

Performance Criterion Require: **B** (Please see following table)

Block diagram of Test setup



5.3.3 Susceptibility performance Criteria and Severity Level

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

	Open Circuit output Test Voltag	e ±10%
Level	On power Supply Lines	On I/O (Input/output)
		Signal data and control lines
1	0.5kV	0.5kV
2	1kV	1kV
3	2kV	2kV
4	4kV	4kV
X	Special	Special

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5.3.4 Test Results

EUT Operating Environment

Temperature: 25 °C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following table for individual results.

Inject location: AC mains

Inject Line	Voltage	Inject	Method	Results
	kV	Times (s)		
L	±1	120	Direct	Pass
N	±1	120	Direct	Pass
L-N	±1	120	Direct	Pass

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5.4 Surge test

5.4.1 Schematics of the test



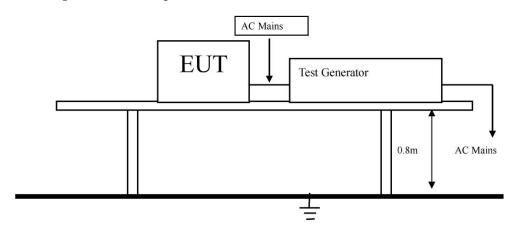
5.4.2 Test Method:

The test was performed in accordance with EN 61000-4-5:2014

Severity: Level 2 (Line to Neutral at 1kV)

Performance Criterion Require: B (Please see following table)

Block diagram of Test setup



5.4.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

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Severity Level

Severity Level	Open-Circuit Test Voltage
	kV
1	0.5
2	1.0
3	2.0
4	4.0
*	Special

5.4.4 Test Results

EUT Operating Environment

Atmospheric Pressure: 101 kPa Temperature: 25°C Humidity: 75%RH

Please refer to the following table for individual results.

Test location:

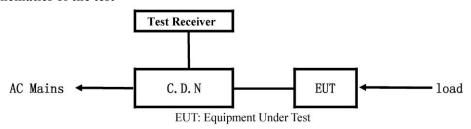
Location	Polarity	Phase	No of	Pulse	Results
		Angle	Pulse	Voltage(kV)	
L-N	+	90	5	1.0	Pass
L-IN	1	270	5	1.0	Pass

Date: 2024-12-27



5.5 Conducted Immunity test

5.5.1 Schematics of the test



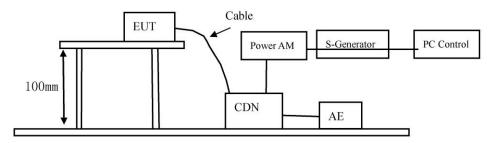
5.5.2 Test Method

The test was performed in accordance with EN 61000-4-6:2014

Severity: Level 2 (3 V rms),0.15MHz—80MHz

Performance Criterion Require: A (Please see following table)

Block diagram of Test setup



5.5.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

Severity Level	Voltage Level (e.m.f) V
1	1
2	3
3	10
*	Special

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5.5.4 Test Results:

EUT Operating Environment

Temperature: 25 °C Humidity: 75%RH Atmospheric Pressure: 101 KPa

Please refer to the following table for individual results.

Frequency	Injected Position	Strength	Criterion	Result
Range (MHz)				
0.15 - 10	AC Line	3V (rms)	A	Pass
10 - 30	AC Line	3 to 1V (rms)	A	Pass
30 - 80	AC Line	1V (rms)	A	Pass

Note: the amplitude of a test level varies over a given frequency range, it changes linearly with respect to the logarithm of the frequency

Date: 2024-12-27



5.6 Power-Frequency magnetic field test

5.6.1 Schematics of the test



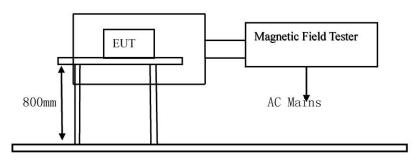
5.6.2 Test Method

The test was performed in accordance with EN 61000-4-8:2010

Severity: Level 1 (1A/m),

Performance Criterion Require: A (Please see following table)

Block diagram of Test setup



5.6.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

Severity Level	Magnetic Field Strength A/m	
1	1	
2	3	
3	10	
4	30	
5	100	
*	Special	

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5.6.4 Test Results:

EUT Operating Environment

Temperature: 25 °C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following table for individual results.

Test Level	Testing Duration	Coil Orientation	Criterion	Result
1A/m	5 Mins	X	A	N/A
1A/m	5 Mins	Y	A	N/A
1A/m	5 Mins	Z	A	N/A

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5.7 Voltage Dips/Interruptions immunity test

5.7.1 Schematics of the test

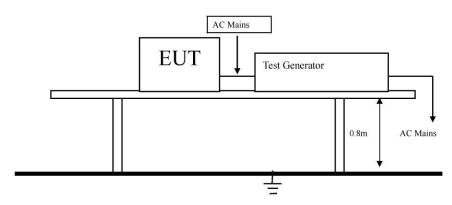


5.7.2 Test Method:

The test was performed in accordance with EN IEC 61000-4-11: 2020

Performance Criterion Require: C&B (Please see following table)

Block diagram of Test setup



5.7.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

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Severity Level

	Test Level %Ut	Reduction	Duration	Performance		
Voltage			(Periods)	Criteria		
Dip	<5	>95	0.5	В		
	70	30	25	С		
	· · · · · · · · · · · · · · · · · · ·					
V-14	Test Level %Ut	Reduction	Duration	Performance		
Voltage			(Periods)	Criteria		
Interceptions	<5	>95	250	C		

5.7.4 Test Result:

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following table for individual results.

Voltage Dip:

Test Level % Ut	Reduction	Duration (periods)	Phase Angle	Meet Criterion	Result
0	100	0.5	0° - 360°	В	Pass
70	30	25	0° - 360°	С	Pass

Voltage Interceptions:

Test Level % Ut	Reduction	Duration (periods)	Phase Angle	Meet Criterion	Result
0	100	250	0° - 360°	С	Pass

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6.0 Product Labelling

6.1 CE Mark label specification

Text of the mark is black or white in color and is left justified. Labels are printed in indelible ink on permanent adhesive backing and shall be affixed at a conspicuous location on the EUT or silk-screened onto the EUT.



6.2 Mark Location: Rear enclosure

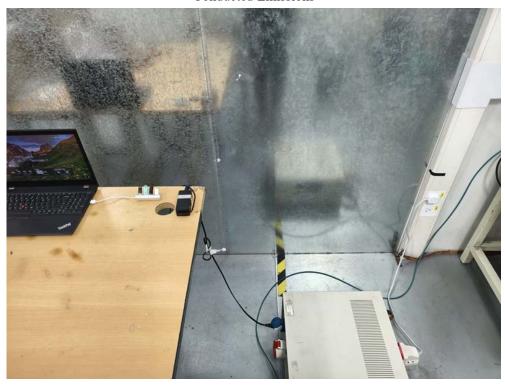
Date: 2024-12-27



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Appendix:

Conducted Emissions



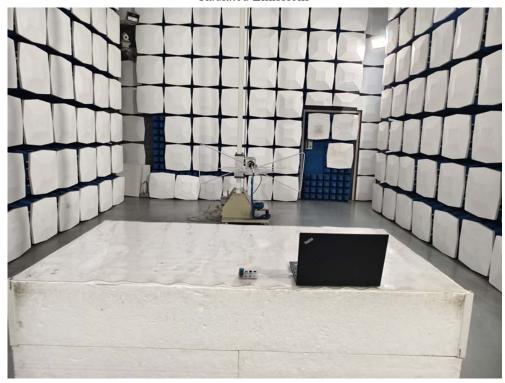
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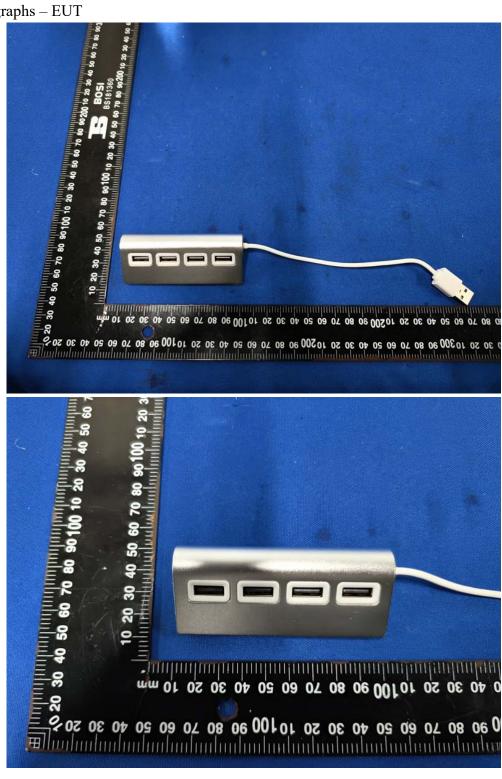
Radiated Emissions



Date: 2024-12-27



Photographs – EUT



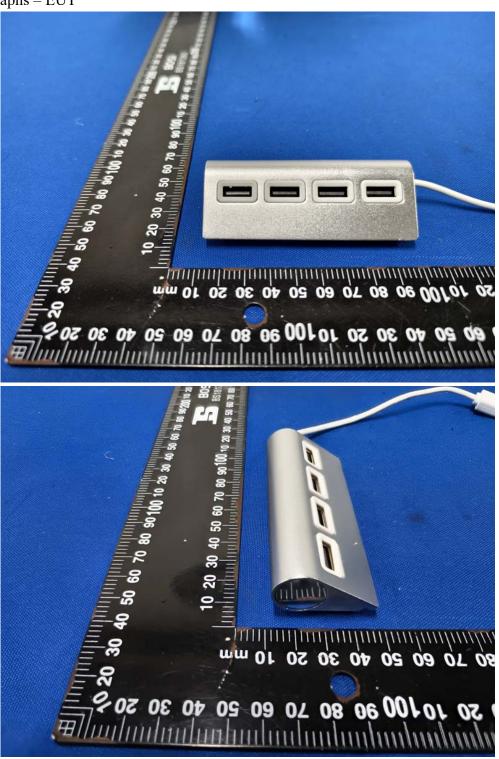
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Photographs – EUT



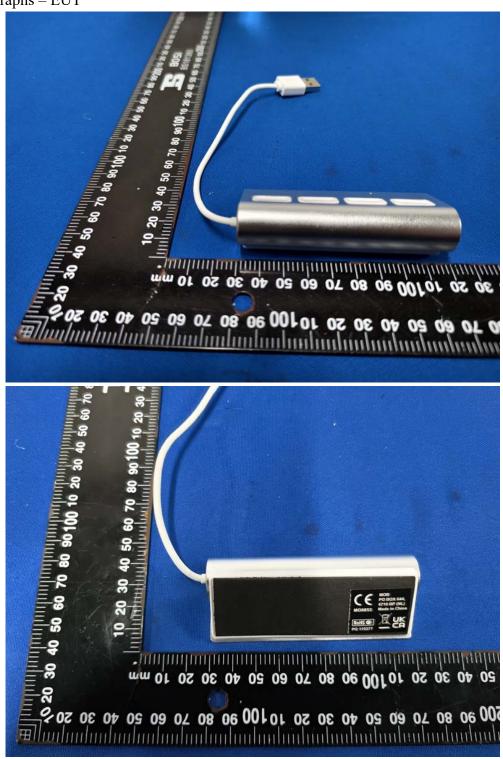
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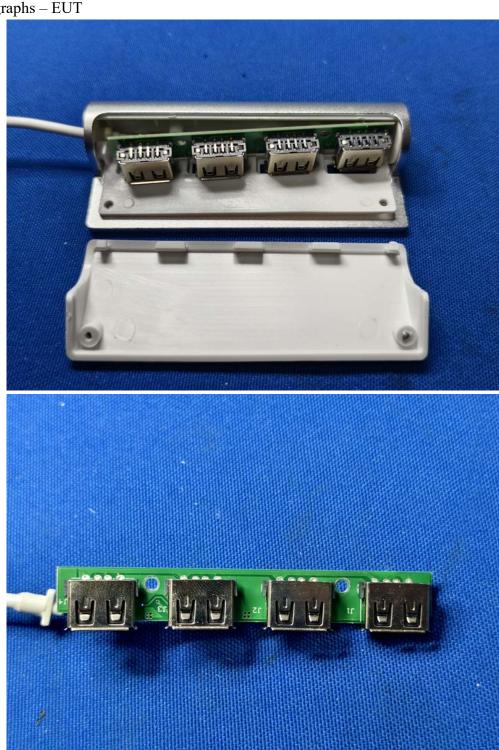
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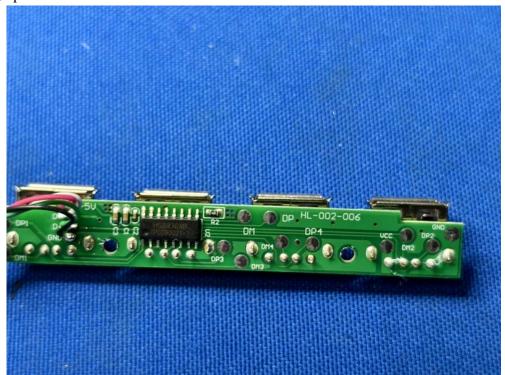
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